

Reduce design cycles by up to 50% with X-parameter measurements

X-parameters* are increasingly being used in place of S-parameters in the design of nonlinear, large signal devices and circuits such as complex power amplifiers, including multi-stage and Doherty circuits. Unlike S-parameters, X-parameters contain detailed and useful information including the magnitudes and phases of distortion products generated by the nonlinear component in response to large signal conditions.

- Use X-parameters instead of S-parameters for large signal, nonlinear devices
- · X-parameters allow you to characterize large signal devices and circuits
- Agilent PNA-X with Maury tuners and software allow X-parameter analysis
- Model and design multi-stage complex amplifiers
- · Simulation models no longer have to be compromised
- Reduces design time by up to 50%

Agilent's load impedance X-parameters option on the PNA-X nonlinear vector network analyzer (NVNA), when used with Maury Microwave's tuners and software. allows you to measure and simulate nonlinear component behavior as a function of impedance, input power, bias and frequency — at all load impedances.

This industry-first approach enables engineers to:

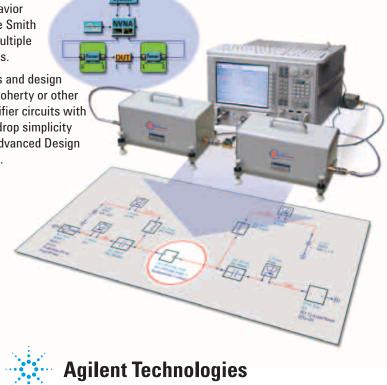
 Extend X-parameter design "cascade-ability" to arbitrarily large load mismatches.

· Automatically measure and simulate accurate, linear and nonlinear behavior over the entire Smith chart under multiple load conditions.

 Model devices and design multi-stage, Doherty or other complex amplifier circuits with the drag-and drop simplicity of Agilent's Advanced Design System (ADS).

The arbitrary load impedance X-parameters option of the PNA-X takes the guesswork out of the typical "trial and error" design approach and eliminates the need to "over design" to safeguard against potential errors.

As a result designers of large signal devices and circuits no longer have to compromise on their simulation models. With this new X-parameter measurement solution from Agilent and Maury you can improve your simulation accuracy, minimize the number of design iterations and reduce your overall design time by up to 50%.





Measure and simulate nonlinear component behavior at all load impedances with X-parameters

System Components

Agilent Technologies

N5242A PNA-X network analyzer N5242A-400 4 ports, dual source

N5242A-419 Extended power range and bias-tees to

4-port analyzer

N5242A-423 Internal combiner and mechanical switches

to 4-port analyzer

N5242A-080 Frequency offset measurements
N5242A-510 Nonlinear component characterization

N5242A-514 Nonlinear X-parameters

U9193C (2 each required), 26.5 GHz Comb Generator

U2002 26.5 GHz USB power sensor (or other Agilent power meter)

Other options are available; contact your local Agilent sales engineer

for more details

Reference documentation publication 5989-8575EN

Maury Microwave

Tuner – select from:

 MT981BU
 0.4 to 4 GHz

 MT982EU30
 0.8 to 8 GHz

 MT983A01
 4 to 26.5 GHz

Plus

MT993B Power measurement software
MT993D01 X-parameter measurement option
Other options are available; contact Maury Sales for more details

For a complete list of Agilent/Maury Solution Briefs: www.agilent.com/find/maurymw



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Maury Microwave

Maury has been in business for 50+ years and has become the world's leading manufacturer of laboratory devices and system components, with an emphasis on device characterization and automated tuning systems.

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